



GE Energy

Functional Testing Specification

Parts & Repair Services
Louisville, KY

LOU-GED-DS200PTBAG1B

Test Procedure for a DS200PTBAG1B card

DOCUMENT REVISION STATUS: Determined by the last entry in the "REV" and "DATE" column

REV.	DESCRIPTION	SIGNATURE	REV. DATE
A	Initial release	Scott Cash	02/01/2011
B	Removed incorrect measurement points	Steve Pharris	03/28/2014
C	Replaced the phrase "test the capacitors" with actual capacitor values to be measured in step 6.2.2.	Cristyn Edlin	07/02/2014
D	Removed Rev C edits and verified IN-CIRCUIT Cap Testing with DMM	J.Barton	08/31/2015

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PREPARED BY Scott Cash	REVIEWED BY S. Pharris	REVIEWED BY J. Barton	QUALITY APPROVAL <i>Charlie Wade</i>
DATE 2/1/2011	DATE 3/28/2014	DATE 8/31/2015	DATE 2/3/2011

LOU-GED-DS200PTBAG1B REV. D	g GE Energy Parts & Repair Services Louisville, KY	Page 2 of 6
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1. SCOPE

1.1 This is a functional testing procedure for a DS200PTBAG.

2. STANDARDS OF QUALITY

2.1 Refer to the current revision of the IPC-A-610 standard for workmanship standards.

3. APPLICABLE DOCUMENTS

3.1 The following document(s) shall form part of this specification to the extent specified herein. Unless otherwise indicated, the latest issue shall apply.

3.1.1 Check board's electronic folder for more information

4. ENGINEERING REQUIREMENTS

4.1 Equipment Cleaning

4.1.1 Equipment should be clean and free of debris prior to applying power unless performing an initial check. Refer to site specific SRA's for cleaning guidelines.

4.2 Equipment Inspection

4.2.1 Equipment should be visually inspected for any defects prior to applying power. This inspection should include the following as a minimum:

4.2.1.1 Wires - broken, cracked, or loosely connected

4.2.1.2 Terminal strips / connectors - broken or cracked

4.2.1.3 Components - visually damaged

4.2.1.4 Capacitors - bloated or leaking

4.2.1.5 Solder joints - damaged or cold

4.2.1.6 Circuit board - burned or de-laminated

4.2.1.7 Printed wire runs / Traces - burned or damaged

5. EQUIPMENT REQUIRED

5.1 The following equipment is required to perform the process requirements. Equipment may be substituted provided that all accuracy's and test ratios are equivalent or better.

Qty	Reference #	Description
1		Fluke 87 DMM (or Equivalent)

6. TESTING PROCESS

6.1 Testing Procedure

6.1.1 Please check the following points. For those reading at 0 ohm, tolerance will be +- 1 ohm. All other readings will be +- 5%.

FROM	TO	Reading in Ohms	Notes
TB-1	JU-1	0	
TB-1	JJR-1	0	
TB-1	JJS-1	0	
TB-1	JJT-1	0	
TB-2	JJR-2	0	
TB-2	JJS-2	0	
TB-2	JJT-2	0	
TB-2	JU-2	0	
TB-3	JU-3	0	
TB-3	JJR-3	0	
TB-3	JJS-3	0	
TB-3	JJT-3	0	
TB-4	JJR-4	0	
TB-4	JJS-4	0	
TB-4	JJT-4	0	
TB-4	JU-4	0	
TB-5	JU-5	0	
TB-5	JJR-5	0	
TB-5	JJS-5	0	
TB-5	JJT-5	0	
TB-6	JJR-6	0	
TB-6	JJS-6	0	
TB-6	JJT-6	0	
TB-6	JU-6	0	
TB-7	JU-7	0	
TB-7	JJR-7	0	
TB-7	JJS-7	0	
TB-7	JJT-7	0	
TB-8	JJR-8	0	
TB-8	JJS-8	0	
TB-8	JJT-8	0	
TB-8	JU-8	0	

FROM	TO	Reading in Ohms	Notes
JU-13	JU-19	1.5K	
JU-13	JU-20	1.5K	
JU-13	JU-21	1.5K	
JU-13	JU-22	1.5K	
JU-13	JU-23	1.5K	
JU-13	JU-24	1.5K	
JU-13	JU-25	1.5K	
JU-13	JU-26	1.5K	
TB-09	JU-9	0	
TB-11	JU-11	0	
TB-10	JU-10	0	
TB-12	JU-12	0	
TB-13	JVA-1	2.7K	
TB-14	JU-19	3.3K	
TB-15	JVB-1	2.7K	
TB-16	JU-20	3.3K	
TB-17	JVA-2	2.7K	
TB-18	JU-21	3.3K	
TB-19	JVB-2	2.7K	
TB-20	JU-22	3.3K	
TB-21	JVA-3	2.7K	
TB-22	JU-23	3.3K	
TB-23	JVB-3	2.7K	
TB-24	JU-24	3.3K	
TB-25	JVA-4	2.7K	
TB-26	JU-25	3.3K	
TB-27	JVB-4	2.7K	
TB-28	JU-26	3.3K	
TB-29	JV-1	155ohms	
TB-30	JV-2	155ohms	
TB-31	JV-3	155ohms	
TB-32	JV-4	155ohms	
TB-33	JV-5	155ohms	
TB-34	JV-6	155ohms	
TB-35	JN-4	0	
TB-36	JN-5	0	
TB-37	JM-6	0	
TB-38	JM-3	0	

FROM	TO	Reading in Ohms	Notes
TB-39	TB-40	0	
TB-41	JN-6	Diode Drop	Negative lead on TB-41
TB-41	TB-38	Diode Drop	Positive lead on TB-41
TB-42	JM-11	0	
TB-43	JN-1	0	
TB-44	TB-45	0	
TB-46	TB-47	0	
TB-48	JN-2	0	
TB-49	JN-2	0	
TB-48	TB-49	0	
TB-50	TB-51	0	
TB-52	TB-53	0	
TB-54	TB-55	0	
TB-56	JN-3	0	
JU-15	JN-7	0	
JU-16	JN-8	0	
JU-14	JN-9	0	
TB-57	JM-1	0	
TB-58	TB-59	0	
TB-58	JM-4	0	
TB-59	JM-4	0	
TB-60	JM-5	0	
TB-61	TB-70	0	
TB-61	JM-2	0	
TB-62	TB-63	0	
TB-62	TB-71	0	
TB-63	TB-71	0	
TB-62	JM-7	0	
TB-63	JM-7	0	
TB-64	JM-8	0	
TB-65	JM-9	0	
TB-66	JM-10	0	
TB-67	TB-62	0	
TB-67	TB-63	0	
TB-67	TB-69	0	
TB-68	JM-12	0	
TB-70	JM-2	0	
TB-61	TB-70	0	
TB-72	JN-10	0	

FROM	TO	Reading in Ohms	Notes
TB-73	TB-74	Diode Drop	~.450
TB-74	TB-73	Diode Drop	~.450
TB-73	JV-7	0	
TB-74	JV-8	0	
TB-75	TB-76	Diode Drop	~.450
TB-76	TB-75	Diode Drop	~.450
TB-75	JV-9	0	
TB-76	JV-10	0	
TB-77	TB-78	Diode Drop	~.450
TB-78	TB-77	Diode Drop	~.450
TB-77	JV-11	0	
TB-78	JV-12	0	
JU-18	JN-12	0	
JU-17	JN-11	0	BJ1 Installed

6.1.2 Capacitor measurements with the DMM.

TB-73	CGND	NEG on CGND	~.175uF
TB-74	CGND	NEG on CGND	~.175uF
TB-75	CGND	NEG on CGND	~.175uF
TB-76	CGND	NEG on CGND	~.175uF
TB-77	CGND	NEG on CGND	~.175uF
TB-78	CGND	NEG on CGND	~.175uF

6.2 ***TEST COMPLETE***

7. NOTES

7.1 None at this time.

8. ATTACHMENTS

8.1 None at this time.